Amendments to the Claims:

The following listing of claims will replace all prior versions, and listings, of claims in the application:

- 1. (Original) A method of producing a single crystal according to Czochralski method comprising the steps of, charging polycrystalline material into a crucible, heating and melting the polycrystalline material by a heater disposed so as to surround the crucible, immersing a seed crystal into the material melt and then pulling the seed crystal to grow a single crystal, wherein in the case of growing a single crystal of which resistivity is controlled by doping with boron, the highest temperature of the crucible is controlled to be 1600°C or less to grow the single crystal.
- 2. (Original) The method of producing a single crystal according to Claim 1, wherein the single crystal doped with boron is grown so that the resistivity of the single crystal to be grown is 0.1Ω cm or less.
- 3. (Currently Amended) The method of producing a single crystal according to Claim 1-or-Claim 2, wherein the single crystal doped with boron is grown so that the resistivity of the single crystal to be grown is 0.001Ω cm or more.
- 4. (Currently Amended) The method of producing a single crystal according to any one of Claims 1—3 Claim 1, wherein the single crystal doped with nitrogen is grown so that concentration of nitrogen in the single crystal to be grown is from 1 x 10¹⁰ /cm³

to $5 \times 10^{15} / \text{cm}^3$.

- 5. (Currently Amended) The method of producing a single crystal according to any one of Claims 1 4 Claim 2, wherein a silicon single crystal is grown as the single crystal.
- 6. (Currently Amended) The method of producing a single crystal according to any one of Claims 1—5Claim 3, wherein in the case of growing the single crystal, a magnetic field of at least 300 gauss or more is applied to the material melt to grow the single crystal.
- 7. (Currently Amended) The method of producing a single crystal according to any one of Claims 1—6Claim 1, wherein a single crystal with a diameter of 200mm or more is grown as the single crystal.
- 8. (New) The method of producing a single crystal according to Claim 2, wherein a silicon single crystal is grown as the single crystal.
- 9. (New) The method of producing a single crystal according to Claim 3, wherein a silicon single crystal is grown as the single crystal.
- 10. (New) The method of producing a single crystal according to Claim 4, wherein a silicon single crystal is grown as the single crystal.

- 11. (New) The method of producing a single crystal according to Claim 5, wherein a silicon single crystal is grown as the single crystal.
- 12. (New) The method of producing a single crystal according to Claim 6, wherein a silicon single crystal is grown as the single crystal.
- 13. (New) The method of producing a single crystal according Claims 7, wherein in the case of growing the single crystal, a magnetic field of at least 300 gauss or more is applied to the material melt to grow the single crystal.
- 14. (New) The method of producing a single crystal according Claims 8, wherein in the case of growing the single crystal, a magnetic field of at least 300 gauss or more is applied to the material melt to grow the single crystal.
- 15. (New) The method of producing a single crystal according Claims 9, wherein in the case of growing the single crystal, a magnetic field of at least 300 gauss or more is applied to the material melt to grow the single crystal.
- 16. (New) The method of producing a single crystal according Claims 10, wherein in the case of growing the single crystal, a magnetic field of at least 300 gauss or more is applied to the material melt to grow the single crystal.

- 17. (New) The method of producing a single crystal according Claims 11, wherein in the case of growing the single crystal, a magnetic field of at least 300 gauss or more is applied to the material melt to grow the single crystal.
- 18. (New) The method of producing a single crystal according Claims 12, wherein in the case of growing the single crystal, a magnetic field of at least 300 gauss or more is applied to the material melt to grow the single crystal.
- 19. (New) The method of producing a single crystal according to Claim 17, wherein a single crystal with a diameter of 200mm or more is grown as the single crystal.
- 20. (New) The method of producing a single crystal according to Claim 18, wherein a single crystal with a diameter of 200mm or more is grown as the single crystal.